


<b>Search Notes</b>  	<b>Application/Control No.</b>  10585323	<b>Applicant(s)/Patent Under Reexamination</b>  TAKAHASHI ET AL.
	<b>Examiner</b>  SHEELA C CHAWAN	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
382	182, 181, 190, 310, 177, 187, 113, 195, 294, 176, 298, 229, 170, 182, 178, 203, 204	12/6/09	SCC
235	462.25, 462.01, 472.01 454	"	"
382	182, 190, 229	6/17/10	SCC
SEARCH UP-DATE		6/17/10	SCC

SEARCH NOTES		
Search Notes	Date	Examiner
SEARCH EAST AND OTHER DATA BASE,	12/6/09	SCC
SEARCH INVENTOR NAME	12/6/09	SCC
SEARCH EAST AND OTHER DATA BASE, SEE THE SEARCH HISTORY	6/17/10	SCC
382/ 182, 180, 190, 310, 177, 187, 113, 195, 294, 176, 298, 229, 170, 182, 178, 203, 204.CCLS. TEXT SEARCH ONLY.	6/17/10	SCC
235/ 462.25, 462.01, 472.01, 454. CCLS. TEXT SEARCH ONLY.	6/17/10	SCC
INTERFERENCE SEARCH	6/17/10	SCC
SEARCH IEEE OR INSPEC DATA BASE.	6/17/10	SCC
SEARCH UP-DATE.	6/17/10	SCC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
382	182, 190, 229	6/17/10	SCC

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